

LIST OF ART CITED BY APPLICANT

(PTO-1449)

ATTY. DOCKET NO.
P-0616APPLN. SERIAL NO.
10/734,206

APPLICANT(S)

Seok II CHANG

FILING DATE
December 15, 2003GROUP
2611

U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE

U.S. PATENT APPLICATION PUBLICATIONS

	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS	

U.S. PATENT APPLICATIONS

	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
/FA/	JP 2001-501798	02/06/2001	Japan (English Abstract and claims and Japanese Full Text)			X	
/FA/	JP 2002-520922	07/09/2002	Japan (English Abstract and claims and Japanese Full Text)			X	

OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)

	Japanese Office Action dated June 2, 2006.

EXAMINER

/Freshteh Aghdam/

DATE CONSIDERED

02/15/2007

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

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GROUP **2631**

U.S. PATENT DOCUMENTS

[illegible]

U.S. PATENT APPLICATION PUBLICATIONS

	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS	

U.S. PATENT APPLICATIONS

	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	
/FA/	US 2002/0012403	01/31/2002	McGowan et al.	375	295	

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
FA	EP 0 716 529 A2	06/12/1996	Europe			X	

OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)

Copy of European Search Report.

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